14th ANNUAL FIB SEM MEETING SCHEDULE

WEDNESDAY MAY 4TH

Thermo Fisher SCIENTIFIC

8:30 – 9:30 EDT	Check-in + Breakfast
9:30 – 9:35	Welcome + Housekeeping
9:35 – 10:20	Invited Tutorial: The History of FIB Applications: From Novelty to Necessity
	Lucille Giannuzzi EXpressLO LLC
	Abstract + Bio
10:20 – 10:50	Invited: (on-line) Multi-Method Characterization Workflow for Advanced Si-based Anodes
	Roland Brunner Materials Center Leoben
	Abstract
10:50 – 11:20	Coffee Break
11:20 – 11:50	Invited: FIB preparation of low melting point metals Joe Michael Independent Consultant
	<u>Abstract</u>
11:50 – 12:05	Strategies for 3D FIB Tomography Data Acquisition to Enable Accurate Materials Modelling and Simulation
	Stephen Kelly Carl Zeiss Research Microscopy Solutions
	<u>Abstract</u>
12:05 – 12:20	Advanced 2D and 3D Characterization of Fiber Optic Nanoparticles using SEM/FIB/TEM
	Rick Passey Thermo Fisher Scientific
	<u>Abstract</u>
12:20 – 12:35	A Stack Alignment Toolbox for Serial Electron Microscopy
	Alex Hall Thermo Fisher Scientific
	<u>Abstract</u>

































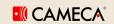
14th ANNUAL FIB SEM MEETING SCHEDULE

WEDNESDAY MAY 4TH

Thermo Fisher SCIENTIFIC

WEDINESD/ (III	5 6
12:35 – 13:30 EDT	Lunch
13:30 – 14:00	Invited: (on-line) Ion Microscopy, Machining, and Elemental Analysis with the Cesium Low Temperature Ion Source (LoTIS)
	Adam Steele zeroK NanoTech
	Abstract
14:00 – 14:15	Novel FIB-nanofabrication strategies with Lithium and Bismuth ions from GaBiLi Liquid Metal Alloy Ion Sources
	Yang Yu Raith
	Abstract
14:15 – 14:30	Cryo-FIB/SEM for Micro-scale Analysis of Solid-state Li-lon Battery Electrolytes
	Fred Meisenkothen NIST
	Abstract
14:30 – 14:45	EDS and EBSD Study of Battery Shell
	Jiancun Rao University of Maryland
	Abstract
14:45 – 15:00	Investigating Early HCoV-229E Virus Mediated Endocytosis Nanoscale Interactions with Focused Ion Beam Scanning Electron Microscopy
	Alyssa Williams McMaster University / FIBICS
	Abstract
15:00 – 15:30	Coffee Break
15:30 – 16:00	Invited: So You Bought a Cryo-Plasma FIB with ToF-SIMS. Now What?
	Jamie Ford University of Pennsylvania
	Abstract

































14th ANNUAL FIB SEM MEETING SCHEDULE

Thermo Fisher SCIENTIFIC

WEDNESDAY MAY 4TH

16:00 – 16:15 **EDT** Informing metallurgical issues related to additively manufacturing using FIB sample preparation for TKD and

TEM analyses

Andy lams NIST

Abstract

16:15 - 16:30 DeepLearning Segmentation of BioSEM Samples is Robust

and High Throughput

Mike Marsh **ORS**

Abstract

16:30 - 16:45 (on-line) Imaging and understanding metal organic

frameworks using advanced scanning electron microscopy

techniques

Maadhav Kothari Carl Zeiss Microscopy

Abstract

16:45 - 17:00 Free

17:00 - 19:00 Happy Hour at the K-Center



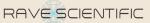






























14th ANNUAL FIB SEM MEETING SCHEDULE

THURSDAY MAY 5TH

Thermo Fisher SCIENTIFIC

8:30 – 9:30 EDT	Check-in + Breakfast
9:30 – 9:35	Welcome + Housekeeping
9:35 – 10:05	Invited: (on-line) Solutions for Characterization of Semiconductors by Combining Plasma FIB Milling, Laser Ablation and Gas-Assisted Delayering
	Lukáš Hladík TESCAN ORSAY HOLDING a.s.
	Abstract
10:05 – 10:25	(on-line) Correlative Raman spectroscopy and electron microscopy studies of Ga FIB and post-FIB Ar ion milling of Si TEM specimens
	Cecile Bonifacio <i>E.A. Fischione Instruments, Inc.</i>
	Abstract
10:25 – 10:45	(on-line) FIB-Induced Unique Self-Organization for 3D Nanostructures on Germanium Surface
	Bhaveshkumar Kamaliya IIT (India Institute of Technology)
	Abstract
10:45 – 11:00	Build your own open-source web viewer for 3D FIB-SEM data
	Joachim de Fourestier FIBICS / McMaster University
	Abstract
11:00 – 11:30	Coffee Break
11:30 – 12:00	Invited: More than Moore: How focused ion beam microscopy is meeting the demands of the semiconductor Industry
	Adam Stokes Thermo Fisher Scientific
	Abstract

































14th ANNUAL FIB SEM MEETING SCHEDULE

THURSDAY MAY 5TH

ThermoFisher SCIENTIFIC

12:00 – 12:30	Invited: FIB TEM Sample Preparation Artifacts in Semiconductors
	Lynne Gignac IBM
	Abstract
12:30 – 13:30 ED	T Lunch
13:30 – 14:00	Invited: 3D tomography on semiconductor samples for defect detection and metrology
	Thomas Korb Carl Zeiss SMT
	Abstract
14:00 – 14:15	Novel Use of EXLO for Cryo-Manipulation of FIB Specimens
	Lucille Giannuzzi EXpressLO LLC
	Abstract
14:15 – 14:30	Reverse Engineering Alligator Gar Fish Scales: Where Biology Meets Materials Science Meets Mineralogy
	Ken Livi Johns Hopkins University
	Abstract
14:30 – 14:45	TEM sample preparation of diverse materials
	Trevor Clark Pennsylvania State University
	Abstract
14:45 – 15:15	Coffee Break
15:15 – 16:00	Invited Tutorial: An Introduction to the FIB as a Microchip Circuit Edit Tool
	Steve Herschbein Independent Consultant
	Abstract + Bio
16:00	Adjourn



